

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Defin	Errors	Ref #
1	BRS	4081	wafer and batch\$3 near1 process\$3	US-PGPUB; USPAT	2004/10/15 16:58				S1
2	BRS	5	S1 and workpiece and tool and state and metrology and rout\$3 and correlation	US-PGPUB; USPAT	2004/10/15 19:44				S2
3	IS&R	1	("6773931").PN.	US-PGPUB; USPAT; USOCR	2004/10/15 19:44				S3
4	BRS	1	S3 and fault	US-PGPUB; USPAT	2004/10/15 19:45				S4
5	BRS	1	S3 and (fault or error)	US-PGPUB; USPAT	2004/10/15 19:45				S5
6	BRS	1	S5 and detect\$3	US-PGPUB; USPAT	2004/10/15 19:51				S6
7	BRS	0	S3 and position	US-PGPUB; USPAT	2004/10/15 19:51				S7
8	BRS	0	S3 and modify\$3	US-PGPUB; USPAT	2004/10/15 19:52				S8
9	BRS	0	S3 and queue	US-PGPUB; USPAT	2004/10/15 19:52				S9
10	BRS	0	S3 and sampl\$3	US-PGPUB; USPAT	2004/10/15 19:53				S10
11	BRS	0	S3 and trigger	US-PGPUB; USPAT	2004/10/15 19:53				S11
12	BRS	1	S3 and trigger\$3	US-PGPUB; USPAT	2004/10/15 19:53				S12
13	BRS	1	"6587744".PN.	USPAT	2004/10/15 19:56				S13
14	BRS	1	"6444481".PN.	USPAT	2004/10/15 19:56				S14
15	BRS	1	"6408220".PN.	USPAT	2004/10/15 19:57				S15
16	BRS	1	"5270222".PN.	USPAT	2004/10/15 19:57				S16
17	BRS	1	"6587744".PN.	USPAT	2004/10/15 19:58				S17

	U	I	P	P	Document ID	Issue Date	Pages	Title	Current OR	Current XR	Retrieval C	Inventor	S	C	3	3
1					US 20040059456 A1	20040325	19	Correlating an inline parameter to a device operation parameter	700/121			Bode, Christopher A. et al.				
2					US 20040029299 A1	20040212	20	Dynamic targeting for a process control system	438/5	700/121		Pasady, Alexander J. et al.				
3					US 20010039462 A1	20011108	28	System and method for predicting software models using material-centric process instrumentation	700/45			Mendez, Rafael et al.				
4					US 6773931 B2	20040810	19	Dynamic targeting for a process control system	438/10	700/121		Pasady, Alexander J. et al.				
5					US 6650955 B1	20031118	9	Method and apparatus for determining a sampling plan based on process and equipment fingerprinting	700/108	438/14; 438/16; 438/17; 438/18; 700/109; 700/		Sonderman, Thomas J. et al.				